

Notice of References CitedApplication/Control No.
09/765,430Applicant(s)/Patent Under Reexam
Nagashima et al.Examiner
Anil KhatriArt Unit
2122

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NON-PATENT DOCUMENTS

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x	X	Jarvinen et al, "Object oriented specification of reactive systems", IEEE, pp 63-71

* A copy of this reference is not being furnished with this Office action. See MPEP § 707.05(a).

¹ Dates in MM-YYYY format are publication dates.² Classifications may be U.S. or foreign.